

Resource Summary Report

Generated by [RRID](#) on Aug 11, 2026

Bruker: ELEXSYS-E580 pulse X-/Q-band system

RRID:SCR_027754

Type: Tool

Proper Citation

Bruker: ELEXSYS-E580 pulse X-/Q-band system (RRID:SCR_027754)

Resource Information

URL: <https://smirnovgroup.wordpress.ncsu.edu/e580-a-shared-x-q-band-instrument/>

Proper Citation: Bruker: ELEXSYS-E580 pulse X-/Q-band system (RRID:SCR_027754)

Description: Bruker ELEXSYS-E580 pulse X-/Q-band instrument offers state-of-the-art capabilities for both standard and cutting-edge EPR spectroscopy across a broad range of sample types and experimental needs. High-performance Electron Paramagnetic Resonance (EPR) spectrometer used for advanced research in chemistry, materials science, biochemistry, and physics, enabling studies of paramagnetic molecules, protein structures, quantum states, and materials by combining X-band (9-10 GHz) and Q-band (34 GHz) frequencies for high-resolution, sensitive pulse techniques.

Synonyms: Bruker ELEXSYS-E580 EPR Spectrometer

Resource Type: instrument resource

Keywords: Electron Paramagnetic Resonance, spectrometer,

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_027754.pdf

Resource Name: Bruker: ELEXSYS-E580 pulse X-/Q-band system

Resource ID: SCR_027754

Alternate IDs: Model_Number_ELEXSYS_E_580

Record Creation Time: 20251209T055453+0000

Record Last Update: 20260808T190808+0000

Ratings and Alerts

No rating or validation information has been found for Bruker: ELEXSYS-E580 pulse X-/Q-band system.

No alerts have been found for Bruker: ELEXSYS-E580 pulse X-/Q-band system.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We found 1 mentions in open access literature.

Listed below are recent publications. The full list is available at [RRID](#) .

Besaw JE, et al. (2026) Structural characterization of the Cu(II)-NTA spin label on ??-helices by X-ray crystallography and electron paramagnetic resonance. Structure (London, England : 1993), 34(4), 645.